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(12) **United States Design Patent**
Ito et al.

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(54) **SUBSTRATE FOR SPECTROSCOPIC ANALYSIS**

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(30) **Foreign Application Priority Data**

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(52) **U.S. Cl.**
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CPC **G01N 1/405** (2013.01)

(58) **Field of Classification Search**

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D10/80, 81; 422/502-507, 430, 560-566,
422/68.1, 69, 547; 435/288.2-288.5,
435/283.1, 289.1, 44, 46

CPC B01J 19/0046; B01J 2219/00596; G01N
1/405; G01N 35/00009; G01N 1/312;
B01L 2300/0816; B01L 2400/0406; B01L
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9/543; B01L 9/00; B01L 3/5085; B01L
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See application file for complete search history.

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Primary Examiner — Richard E Chilcot

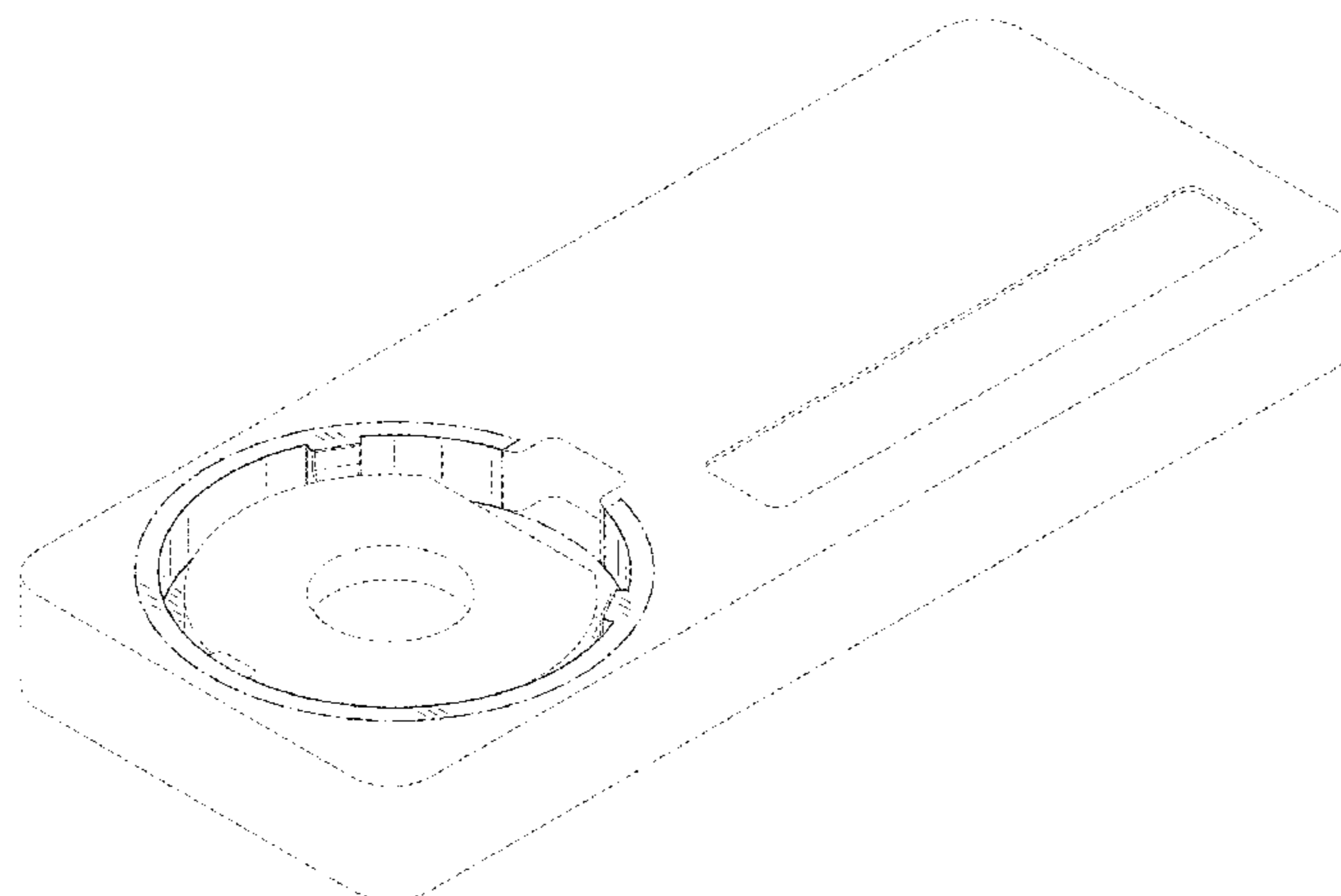
(57) **CLAIM**

The ornamental design for a substrate for spectroscopic analysis, as shown and described.

DESCRIPTION

- 1. Substrate for spectroscopic analysis
- 1.1 : Perspective
- 1.2 : Front
- 1.3 : Back
- 1.4 : Top
- 1.5 : Bottom
- 1.6 : Left
- 1.7 : Right
- 1.8 : SECTIONAL VIEW
- 1.9 : SECTIONAL VIEW
- 1.10 : PERSPECTIVE VIEW WITHOUT THE COVER PART

(Continued)



The broken line showing the substrate for spectroscopic analysis is for the purpose of illustrating environmental structure and forms no part of the claimed design.

The dot-dash broken lines define the bounds of the claimed design and form no part thereof.

1 Claim, 10 Drawing Sheets

(56)

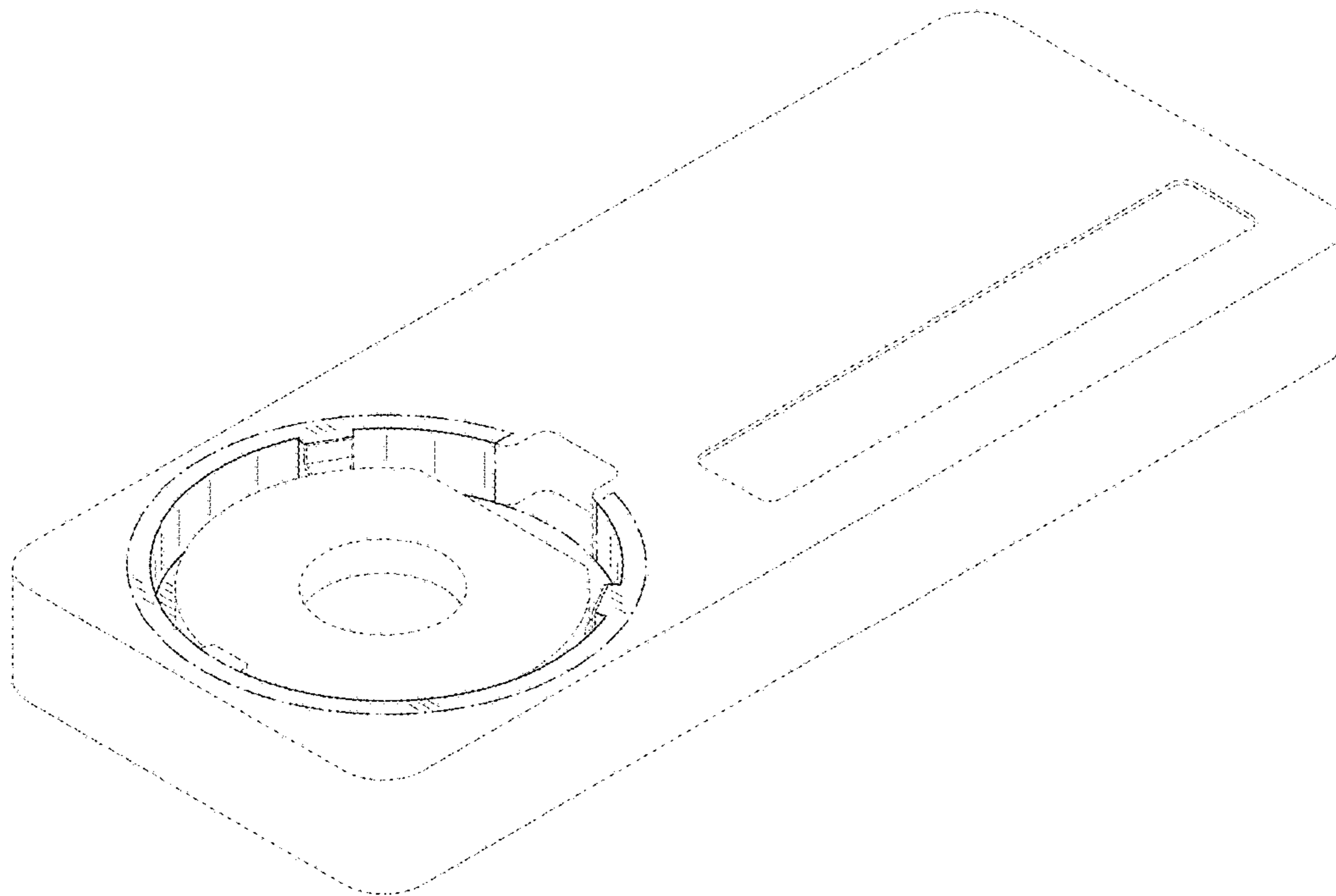
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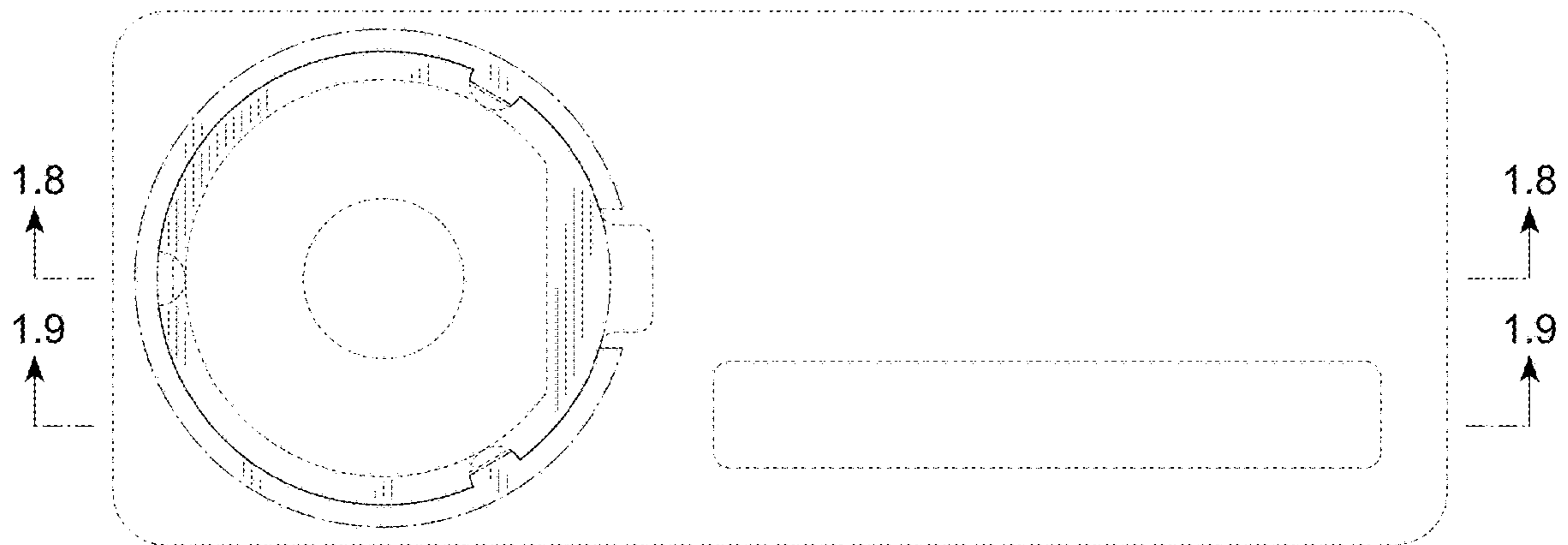
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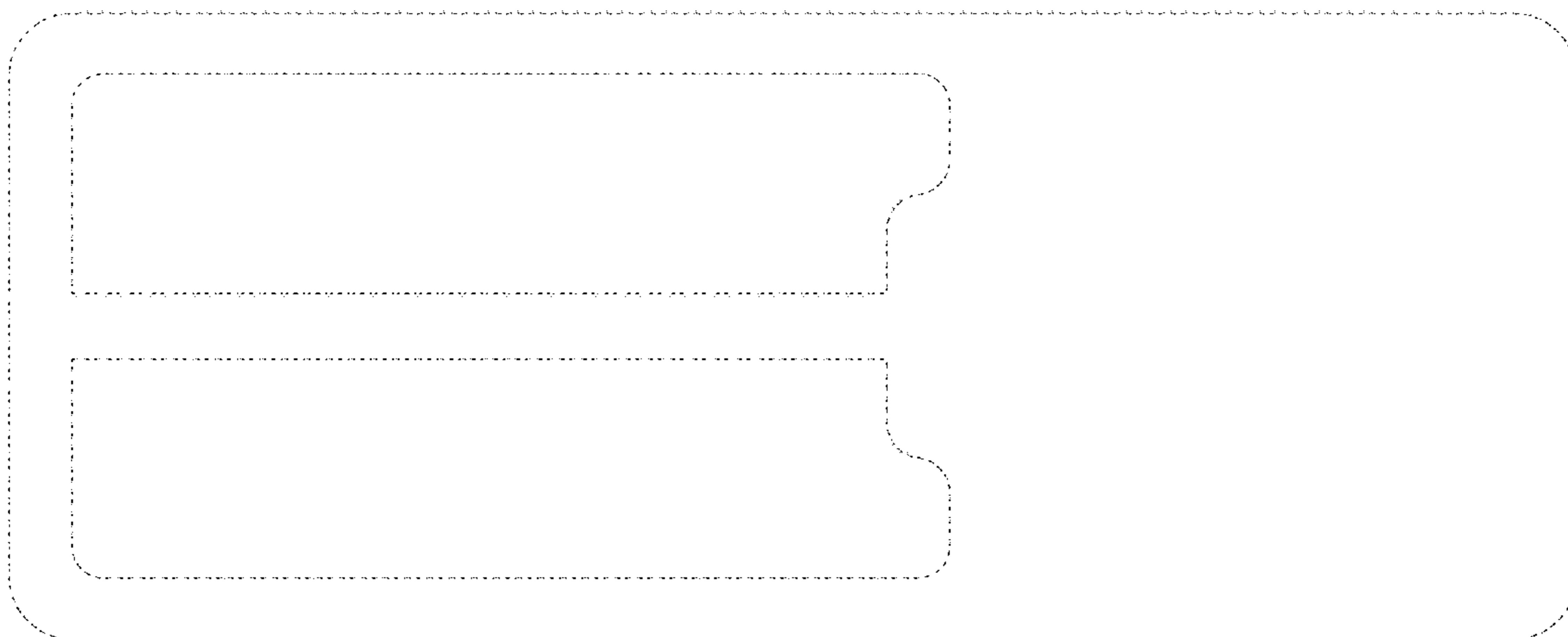
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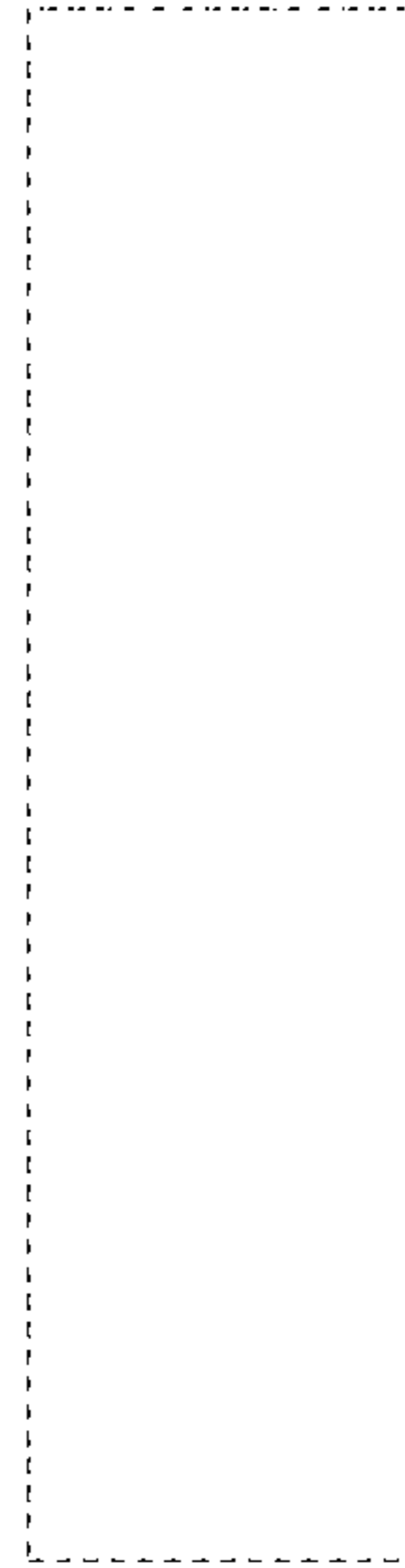
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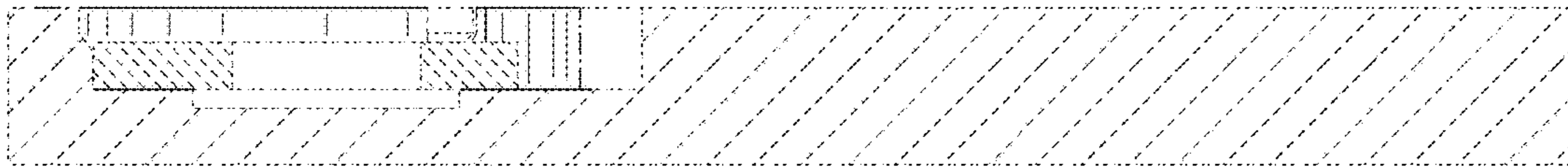
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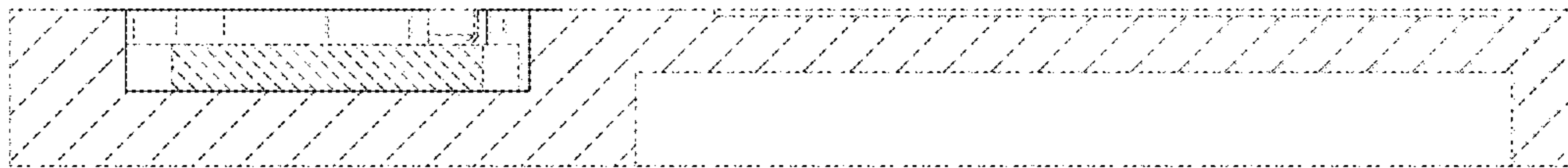
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1.8



1.9



1.10

